

L Number	Hits	Search Text	DB	Time stamp
1	1493	(wafer sample substrate work) with (diameter length width height size) with ("300 mm" "300 millimeters" "72 in" "72 inches")	USPAT	2004/09/19 22:13
2	87	(wafer sample substrate work) with (diameter length width height size) with ("300 mm" "300 millimeters" "72 in" "72 inches")	JPO; DERWENT	2004/09/19 22:12
4	121	((wafer sample substrate work) with (diameter length width height size) with ("300 mm" "300 millimeters" "72 in" "72 inches")) and (118/723\$.ccls. 156/345\$.ccls.)	USPAT	2004/09/19 22:14
5	4	("4565601" "4968374" "5350479" "5591269").PN.	USPAT	2004/09/19 22:11
8	1954	(wafer sample substrate work) with (diameter length width height size) with ("300 mm" "300 millimeters" "12 in" "12 inches")	USPAT	2004/09/19 22:14
9	146	((wafer sample substrate work) with (diameter length width height size) with ("300 mm" "300 millimeters" "12 in" "12 inches")) and (118/723\$.ccls. 156/345\$.ccls.)	USPAT	2004/09/19 22:19
10	25	((wafer sample substrate work) with (diameter length width height size) with ("300 mm" "300 millimeters" "12 in" "12 inches")) and (118/723\$.ccls. 156/345\$.ccls.) not ((wafer sample substrate work) with (diameter length width height size) with ("300 mm" "300 millimeters" "72 in" "72 inches")) and (118/723\$.ccls. 156/345\$.ccls.)	USPAT	2004/09/19 22:18
11	567	plasma with density with ("cm" centimeters "mm" millimeters meters)	USPAT	2004/09/19 22:19
12	159	(plasma with density with ("cm" centimeters "mm" millimeters meters)) and (118/723\$.ccls. 156/345\$.ccls.)	USPAT	2004/09/19 22:19
13	155	((361/234; 156/345.35; 156/345.48; 156/345.47; 156/345.44; 156/345.43; 156/345.42; 156/345.41; 156/345.38; 156/345.36; 279/128; 118/723e; 118/723mw; 118/723mr; 118/723ma; 118/723er; 118/723i; 118/723ir).CCLS.) not @pd<=20040101	USPAT	2004/09/19 22:29